

Workshop on sapphire detector construction

Report of Contributions

Contribution ID: 1

Type: **not specified**

Introduction

Thursday, 11 January 2024 09:15 (5 minutes)

Presenter: MORANDIN, Mauro (Istituto Nazionale di Fisica Nucleare)

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 2

Type: **not specified**

Microstrip sensor production at Tomsk

Thursday, 11 January 2024 09:20 (10 minutes)

Presenter: Dr TYAZHEV, Anton (Tomsk University)

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 3

Type: **not specified**

Microstrip sensor production at FBK

Thursday, 11 January 2024 09:30 (10 minutes)

Presenter: MARGESIN, Benno (FBK Trento)

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 4

Type: **not specified**

Experience with diamond metallization and effect of non-ohmic contacts

Thursday, 11 January 2024 09:40 (20 minutes)

Presenter: Dr TRUCCHI, Daniele (CNR Montelibretti)

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 5

Type: **not specified**

Strip resistivity

Thursday, 11 January 2024 10:00 (5 minutes)

Presenters: GRUTTA, Pietro (Istituto Nazionale di Fisica Nucleare); VASIUKOV, Sergii; VASIUKOV, Sergii (Istituto Nazionale di Fisica Nucleare)

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 6

Type: **not specified**

Discussion: lesson learnt, suggestions for future productions

Thursday, 11 January 2024 10:05 (10 minutes)

Presenter: ALL

Session Classification: Sapphire procurement and electrode deposition at Tomsk and FBK

Contribution ID: 8

Type: **not specified**

Measurements in Tomsk

Thursday, 11 January 2024 10:45 (10 minutes)

Presenter: Dr TYAZHEV, Anton (Tomsk University)

Session Classification: Characterization and qualification of sapphire sensors with X-rays

Contribution ID: 9

Type: **not specified**

Measurements in Padova

Thursday, 11 January 2024 10:55 (10 minutes)

Presenters: VASIUKOV, Sergii; VASIUKOV, Sergii (Istituto Nazionale di Fisica Nucleare)

Session Classification: Characterization and qualification of sapphire sensors with X-rays

Contribution ID: **10**

Type: **not specified**

Diamond measurements under irradiation and measurement of CCE and mu-tau

Thursday, 11 January 2024 11:05 (20 minutes)

Presenter: Dr TRUCCHI, Daniele (CNR Montelibretti)

Session Classification: Characterization and qualification of sapphire sensors with X-rays

Contribution ID: 11

Type: **not specified**

Discussion: exploitation of X-rays for future sapphire characterization, possibility of disentangling and mitigating non-ohmic contact effects

Thursday, 11 January 2024 11:25 (20 minutes)

Presenter: ALL

Session Classification: Characterization and qualification of sapphire sensors with X-rays

Contribution ID: 12

Type: **not specified**

Measurements of CCE with pad sensors and an alpha source, plasma effects

Thursday, 11 January 2024 12:05 (10 minutes)

Presenter: MORANDIN, Mauro (Istituto Nazionale di Fisica Nucleare)

Session Classification: Measuring CCE and mu-tau for sapphire sensors

Contribution ID: 13

Type: **not specified**

Measurements of CCE with pad sensors with a low intensity electron beam

Thursday, 11 January 2024 12:15 (10 minutes)

Presenter: GRUTTA, Pietro (Istituto Nazionale di Fisica Nucleare)

Session Classification: Measuring CCE and mu-tau for sapphire sensors

Contribution ID: 15

Type: **not specified**

Discussions: how to improve the current evaluations of CCE and mu-tau

Thursday, 11 January 2024 12:25 (25 minutes)

Presenter: ALL

Session Classification: Measuring CCE and mu-tau for sapphire sensors

Contribution ID: **16**

Type: **not specified**

Follow-up Discussion

Thursday, 11 January 2024 13:05 (20 minutes)

Presenters: TYAZHEV, Anton; BRUSCHI, Marco (Istituto Nazionale di Fisica Nucleare); MORANDIN, Mauro (Istituto Nazionale di Fisica Nucleare); VASIUKOV, Sergii